

Notice of References Cited	Application/Control No. 10/663,714	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0127394	06-2005	Nagahama et al.	257/103
	B	US-			
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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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